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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/721,911	CHIBA ET AL.	
Examiner	Art Unit	
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Class	Subclass	Date	Examiner
327	291, 298, 333, 108, 156-158,	9/1/2005	DL
327	231, 256	9/1/2005	DL
327	258	9/1/2005	DL
326	30, 86	9/1/2005	DL
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
327	see above	9/1/2005	DL	
326	See above	9/1/2005	DL	

SEARCH NO (INCLUDING SEARCH)
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